

Search Notes

Application/Control No.

10/605,308

Examiner

Anh D. Mai

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

2814

SEARCHED

Class	Subclass	Date	Examiner
257	758; 775	1/11/2005	A.M
438	182; 574 579	1/11/05	A.M

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (all): * Inventors * CCLS * (inverse T) and FET * (T-shape\$ gate) or (T gate) and semiconductor and FET and substrate. * borderless contact	1/11/05	A.M
Web: PAJ	1/11/2005	A.M